

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

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Application Number	10/587,303
Confirmation Number	6535
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Art Unit	2886
Examiner Name	Tara S PAJOOHI
Attorney Docket Number	Q96164

## U.S. PATENTS

Examiner Initials*	Cite No	Patent Number	Kind Code <sup>1</sup>	Issue Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
1.						

## U.S. PATENT APPLICATION PUBLICATIONS

Examiner Initials*	Cite No	Publication Number	Kind Code <sup>1</sup>	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No	Foreign Document Number <sup>3</sup>	Country Code <sup>2</sup>	Kind Code <sup>4</sup>	Publication Date	Name of Patentee or Applicant of cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>5</sup>
1.	2003-195085	JP	A	2003-07-09	Fitel USA Corp			

## NON-PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	T <sup>5</sup>
	1.	Shin-Etsu Quartz Products Co., Ltd., "Quartz Glass Technical Guide - 1 Chemical and Physical Properties of Quartz Glass", p. 7, Tokyo, Japan, October 1, 2005. (available at: <a href="http://www.sqp.co.jp/seihin/catalog/pdf/q1.pdf">http://www.sqp.co.jp/seihin/catalog/pdf/q1.pdf</a> )	
	2.	Shin-Etsu Quartz Products Co., Ltd., "Quartz Glass Technical Guide - 2 Optical Properties of Quartz Glass", p. 7, Tokyo, Japan, October 1, 2005. (available at: <a href="http://www.sqp.co.jp/seihin/catalog/pdf/q2.pdf">http://www.sqp.co.jp/seihin/catalog/pdf/q2.pdf</a> )	
	3.	The Institute of Electrical and Electronics Engineers, Inc. (IEEE), "802.3ae: IEEE Standard for Information Technology – Telecommunications and information exchange between systems – Local and metropolitan area networks – Specific requirements, Part 3", pages 401-443, New York, NY August 30, 2002.	
	4.	International Electrotechnical Commission (IEC), "IEC/PAS 60793-1-49 Edition 1.0, Pre-Standard Optical fibres – Part 1-49: Measurement methods and test procedures – Differential mode delay", Geneva Switzerland, May 2005.	
	5.	International Electrotechnical Commission (IEC), "IEC 60793-2-10 Ed. 2.0: Optical Fibres – Part 2-10: Product specifications – Sectional specification for category A1 multimode fibres", Geneva, Switzerland July 23, 2004	

## EXAMINER SIGNATURE

Examiner Signature		Date Considered
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3 For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. 4 Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. 5 Applicant is to place a check mark here if English language translation is attached.